



Description

The AP5P04MI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -40V I_{D} = -5.0A$

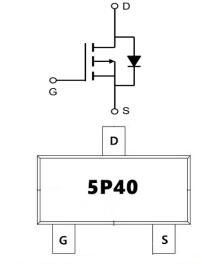
 $R_{DS(ON)} < 72m\Omega$ @ V_{GS} =-10V (Type: 65m Ω)

Application

Battery protection

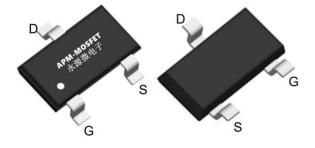
Load switch

Uninterruptible power supply



Top View

Bottom View



Package Marking and Ordering Information

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Product ID	Pack	Marking	Qty(PCS)		
AP5P04MI	SOT23-3L	5P40	3000		

Absolute Maximum Ratings (T_c=25°C unless otherwise noted)

Symbol	Parameter	Steady State	Units
VDS	Drain-Source Voltage	Drain-Source Voltage -40	
VGS	Gate-Source Voltage	±20	V
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ -4.5V ¹	-5.0	А
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ -4.5V ¹	-3.0	А
IDM	Pulsed Drain Current ²	-16.1	А
P _D @T _A =25℃	Total Power Dissipation ³	1.32	W
P _D @T _A =70°C	Total Power Dissipation ³	0.84	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R _θ JA	Thermal Resistance Junction-Ambient ¹	125	°C/W
R₀JC	Thermal Resistance Junction-Case ¹	80	°C/W



Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-40	-46		V	
∆BVDSS/∆TJ	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.018		V/°C	
DDC(ON)	Static Drain-Source On-Resistance ²	V _{GS} =-4.5V , I _D =-3A		65	72	mΩ	
RDS(ON)		V _{GS} =-2.5V , I _D =-2A		89	100		
VGS(th)	Gate Threshold Voltage	\/ \/ L 050 A	-1.0	-1.5	-2.5	V	
$\triangle V_{GS(th)}$	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, I_{D} =-250uA		2.5		mV/°C	
IDSS	Drain Source Leakage Current	V _{DS} =-24V , V _{GS} =0V ,T _J =25°C			-1	uA	
וטסס	Drain-Source Leakage Current	V _{DS} =-24V , V _{GS} =0V ,T _J =55°C			-5		
IGSS	Gate-Source Leakage Current	V _{GS} =±20V , V _{DS} =0V			±100	nA	
gfs	Forward Transconductance	V _{DS} =-5V , I _D =-3A		5.8		S	
Qg	Total Gate Charge (-4.5V)			6.4		nC	
Qgs	Gate-Source Charge	V_{DS} =-32V , V_{GS} =-4.5V , I_{D} =-		2.1			
Qgd	Gate-Drain Charge			2.5			
Td(on)	Turn-On Delay Time			4.2			
Tr	Rise Time	V _{DD} =-20V , V _{GS} =-4.5V ,		23		ns	
Td(off)	Turn-Off Delay Time	R _G =3.3Ω, I _D =-3A		26.8			
T _f	Fall Time	1		20.6			
Ciss	Input Capacitance	V _{DS} =-15V , V _{GS} =0V , f=1MHz		620		pF	
Coss	Output Capacitance			65			
Crss	Reverse Transfer Capacitance]		53			
IS	Continuous Source Current ^{1,4}	\/ -\/ -0\/ Farra C:			-5.2	Α	
ISM	Pulsed Source Current ^{2,4}	V _G =V _D =0V , Force Current			-16.1	Α	
VSD	Diode Forward Voltage ²	V _{GS} =0V , I _S =-1A , T _J =25°C			-1	V	

Note:

- $1 \, {\mbox{\tiny ∞}}$ The data tested by surface mounted on a 1 inch FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width $\leqq 300 us$, duty cycle $\leqq 2\%$
- 3. The power dissipation is limited by 150°C junction temperature
- $4\sqrt{100}$ The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.





Typical Characteristics

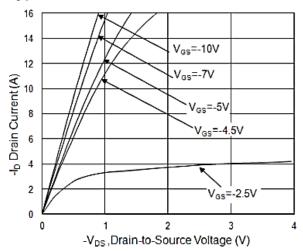


Fig.1 Typical Output Characteristics

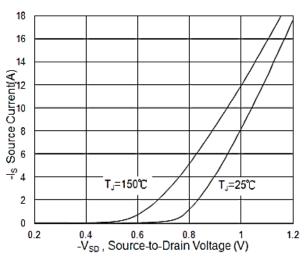


Fig.3 Forward Characteristics Of Reverse

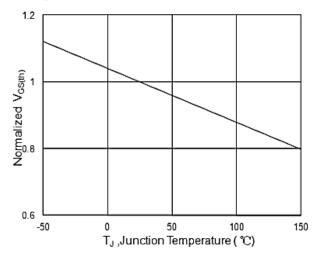


Fig.5 Normalized V_{GS(th)} vs. T_J

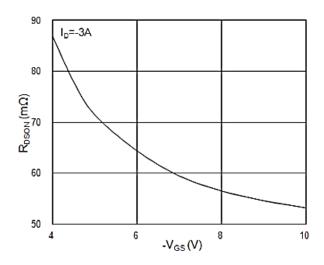


Fig.2 On-Resistance vs. G-S Voltage

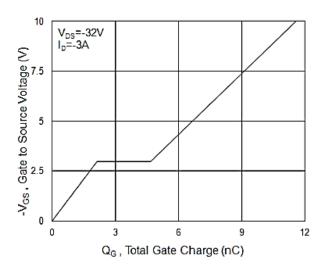


Fig.4 Gate-Charge Characteristics

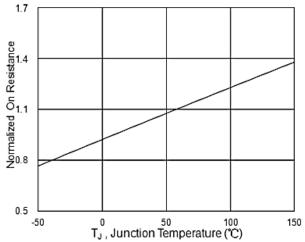
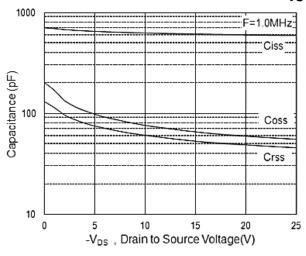


Fig.6 Normalized RDSON vs. TJ







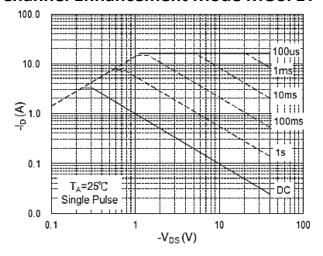


Fig.7 Capacitance

Fig.8 Safe Operating Area

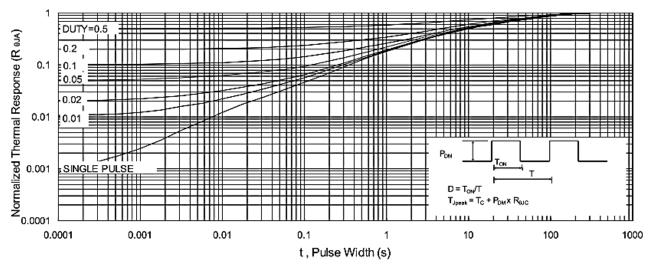
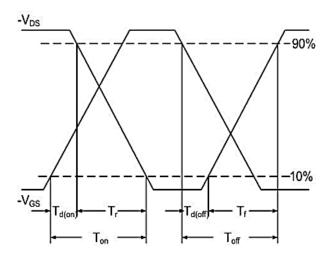


Fig.9 Normalized Maximum Transient Thermal Impedance



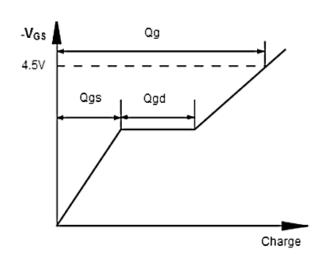
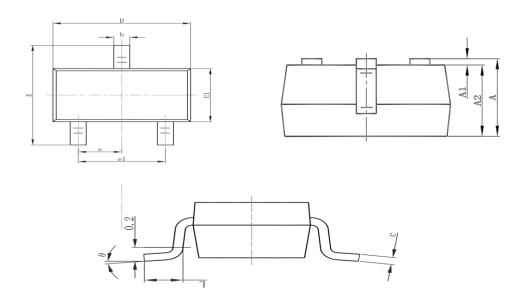


Fig.10 Switching Time Waveform

Fig.11 Gate Charge Waveform



Package Mechanical Data:SOT23-3L



Cymahal	Dimensions	n Millimeters	Dimension	ns In Inches
Symbol	Min.	Max.	Min.	Max.
Α	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
Е	2.650	2.950	0.104	0.116
е	0.950(BSC)		0.037	7(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°





-40V P-Channel Enhancement Mode MOSFET Attention

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